

**Qualification Description:**

The information contained herein represents proof of Reliability and Performance of the Package Series listed below in accordance with the Qualification Plan and test methods referenced in Section 7.0, after exposure to a variety of environments and mechanical events that occur during installation and operational lifetime of the product. Upon conclusion of the testing the product continued to operate within specification limits, demonstrating its capability of reliable operation throughout its lifetime.

The purpose of this report is to present Qualification Test results of the referenced Package Series. The Pericom product data presented in this report qualifies the products manufactured in this package configuration, using the same bill of materials and assembled by the identified subcontractor location. The report describes the qualification test program, procedures utilized, criteria enforced (at the time of product validation), and specific result data obtained during the testing of three lots of semiconductors. The three lots consist of an equal number of units from different date codes, from the same production line and SubContractor to ensure manufacturing repeatability.

**Lot Background Information:**

Qual Vehicle:	PI2DDR3212ZLE
Supplier (Code):	GTK (G)
Pkg Type - Code:	TQFN-52 (ZL52)
Outline Drawing:	PD-2101
By Extension Pkg:	none

Qual Test Date:	Jan-2013 updated Feb-2015
Die Attach Material:	1076DJ-G
Wire Size & Material:	0.8 mil PdCu
Mold Compound:	G770HJ
Leadframe Material:	A194 Copper
Lead Finish:	100% Matte Sn

Date Codes: 1240GG 1409GG 1410GG

**Pericom's Qualification Test Results:**

Stress Test	Test Procedure	Test Conditions	Duration	# of Lots	Samples per Lot	Results Pass/Fail
Preconditioning	JESD22-A113	MSL1	NA	3	154	462 / 0
CSAM	J-STD-020	No delamination of Die Top, Wire bond, Down bond areas	NA	3	22	66 / 0
PreCon UHAST	JESD22-A118	130°C, RH 85%, 33.3 psia, 0V	96 hrs	3	77	231 / 0
PreCon BHAST	JESD22-A118	130°C, RH 85%, 33.3 psia, 3.6V	96 hrs	3	77	231 / 0
via PI3VDP411LSZBE (ZB48)		130°C, RH 85%, 33.3 psia, 3.6V	192 hrs	3	15	45 / 0
PreCon Temp Cycle	JESD22-A104	-65°C to +150°C 500 Cycles	100 cycles	3	77	231 / 0
		-65°C to +150°C 500 Cycles	500 cycles	3	77	231 / 0
HTSL (no PreCon)	JESD22-A103	1000hrs, 0V, 150°C	500 hrs	3	77	231 / 0
		1000hrs, 0V, 150°C	1000 hrs	3	77	231 / 0
Physical Dimension	JESD22-B100	Per Datasheet	NA	3	5	15 / 0
External Visual Insp	JESD22-B101	NA	NA	3	5	15 / 0
Solderability	J-STD-020 JESD22-B102	Pb-Free Solder Dip 245°C	NA	3	5	15 / 0

**Qualificaton by Extension Information:**

Where a product of interest is not sampled during this period, it is valid to use the reliability data of the particular process technology or package type family to which the part belongs. All parts within the same family are designed to the same rules, and manufacturing is controlled by SPC. Within a product family, a device can only be fabricated on one process technology/ option, and only assembled on one package type process.

If there are any questions about this qualification, please contact Quality Support at:

[customerquestion@pericom.com](mailto:customerquestion@pericom.com)

Date: Jan-2013 updated Feb-2015

PKG Type & Code: TQFN-52 (ZL52)

Assembler-Code: GTK (G)

Qual Vehicle: PI2DDR3212ZLE

**By extension: Pericom active devices using the Fab/Process at the time of the Qualification:**

PI2DDR3212ZLE				
PI2DDR3212ZLEX				
PI3WVR12612ZLE				
PI3WVR12612ZLEX				